

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,937,048 B2
APPLICATION NO. : 10/021746
DATED : August 30, 2005
INVENTOR(S) : Eichen et al.

Page 1 of 2

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Replace sheet 3 with the attached formal Fig. 3.

Title page,

Item [57], **ABSTRACT**, delete and replace with the following:

-- An integrated circuit can be tested externally without requiring additional testing output pins or test measuring pads. In the new method, the circuit functions are tested by using the output pins at which the output signal is present during normal operation of the integrated circuit. A defined voltage value is applied to the signal output pin. An integrated control unit evaluates the applied voltage value, and in response thereto switches the integrated circuit into a test mode in which it applies selected signals, which are to be tested, at the signal output pin. --;

Column 3,

Line 34, after "value", replace "Bet" by -- set --;

Line 37, after "window" delete "of the";

Column 4,

Line 24, after "line" delete ",";


Line 53, after "unchanged" replace "acceptionally" by -- or optionally --;

Column 5,

Line 49, after "SE1" insert -- (MS) --.

Signed and Sealed this

Fourth Day of July, 2006

A handwritten signature in black ink, appearing to read "Jon W. Dudas". The signature is stylized with a large, looped initial "J" and a cursive "Dudas".

JON W. DUDAS
Director of the United States Patent and Trademark Office

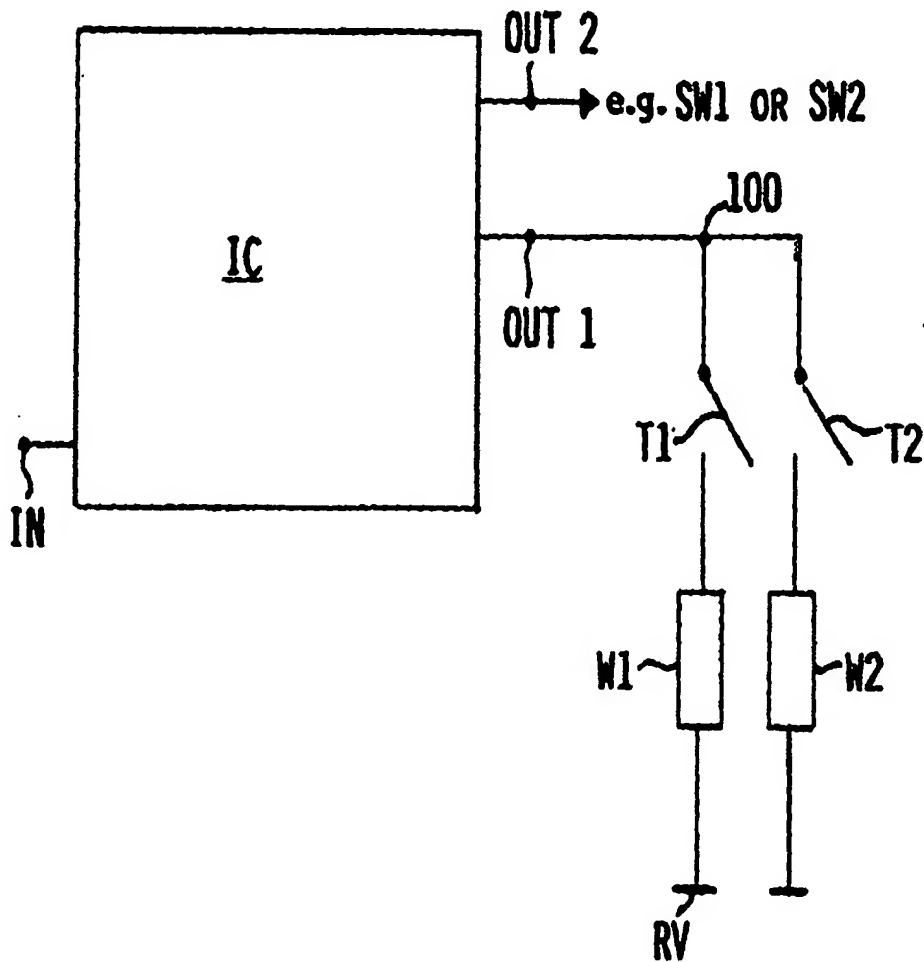


FIG. 3